

TMG70N10P

N-Channel Enhancement Mosfet

General Description

- Low $R_{DS(ON)}$
- RoHS and Halogen-Free Compliant

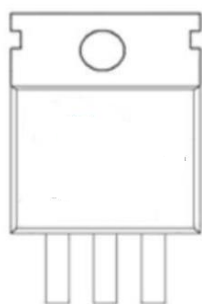
Applications

- Load switch
- PWM

General Features

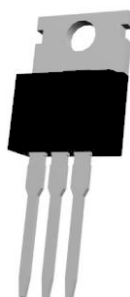
$V_{DS} = 100V$ $I_D = 70A$
 $R_{DS(ON)} = 8.5m\Omega (typ.) @ V_{GS} = 10V$

100% UIS Tested
 100% R_g Tested

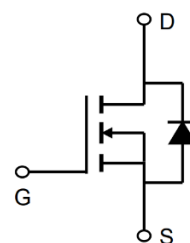


Marking: 70N10

P:TO-220AB



G D S



Absolute Maximum Ratings: ($T_C = 25^\circ C$ unless otherwise noted)

Symbol	Parameter		Value	Units
V_{DSS}	Drain-to-Source Voltage		100	V
I_D	Continuous Drain Current	$T_C = 25^\circ C$	70	A
	Continuous Drain Current	$T_C = 100^\circ C$	45	A
I_{DM}^{a1}	Pulsed Drain Current		259	A
E_{AS}^{a2}	Single pulse avalanche energy		110	mJ
V_{GS}	Gate-to-Source Voltage		± 20	V
P_D	Power Dissipation		100	W
T_J, T_{STG}	Operating Junction and Storage Temperature Range		150, -55 to 150	$^\circ C$
T_L	Maximum Temperature for Soldering		260	$^\circ C$

Thermal Characteristics:

Symbol	Parameter	Value	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	1.25	$^\circ C/W$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	64	$^\circ C/W$

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Electrical Characteristics (TA= 25°C unless otherwise specified):

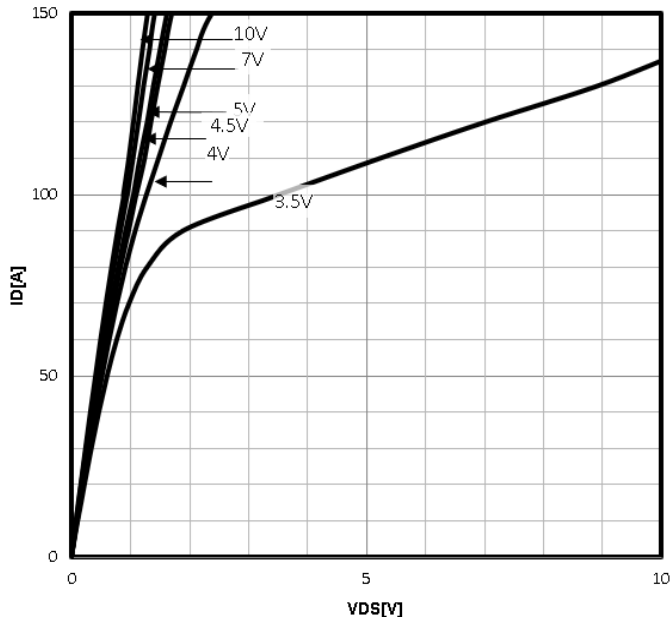
Static Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
V _{DSS}	Drain to Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	100	--	--	V
I _{DSS}	Drain to Source Leakage Current	V _{DS} =100V, V _{GS} =0V	--	--	1	μA
I _{GSS(F)}	Gate to Source Forward Leakage	V _{GS} =+20V, V _{DS} =0V	--	--	100	nA
I _{GSS(R)}	Gate to Source Reverse Leakage	V _{GS} =-20V, V _{DS} =0V	--	--	-100	nA
V _{GS(TH)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	1.3	1.8	2.3	V
R _{DS(ON)}	Drain-to-Source On-Resistance	V _{GS} =10V, I _D =20A	--	8.5	10.5	mΩ
		V _{GS} =4.5V, I _D =15A		11	15	mΩ
Dynamic Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
C _{iss}	Input Capacitance	V _{GS} = 0V V _{DS} = 50V f = 1.0MHz	--	1368	--	pF
C _{oss}	Output Capacitance		--	451	--	
C _{rss}	Reverse Transfer Capacitance		--	12.9	--	
R _g	Gate resistance	V _{GS} =0V,V _{DS} Open	--	0.48	--	Ω
Resistive Switching Characteristics						
Symbol	Parameter	Test Conditions	Value			Units
			Min.	Typ.	Max.	
t _{d(ON)}	Turn-on Delay Time	I _D =10A V _{DS} = 50V V _{GS} = 10V R _G = 4Ω	--	16	--	ns
t _r	Rise Time		--	10	--	
t _{d(OFF)}	Turn-Off Delay Time		--	40	--	
t _f	Fall Time		--	6	--	
Q _g	Total Gate Charge	V _{GS} =10V	--	31.3	--	nC
Q _{gs}	Gate Source Charge	V _{DS} = 50V	--	3.49	--	
Q _{gd}	Gate Drain Charge	I _D =10A	--	7.63	--	
Source-Drain Diode Characteristics						
Symbol	Parameter	Test Conditions	Value			Value
			Min.	Typ.	Max.	
I _S	Diode Forward Current	T _C =25 °C	--	--	70	A
V _{SD}	Diode Forward Voltage	I _S =10A, V _{GS} =0V	--	--	1.2	V
t _{rr}	Reverse Recovery time	I _S =10A, V _{DD} =50V	--	103	--	ns
Q _{rr}	Reverse Recovery Charge	dI/dt=100A/μs	--	187	--	nC

a1: Repetitive rating; pulse width limited by maximum junction temperature

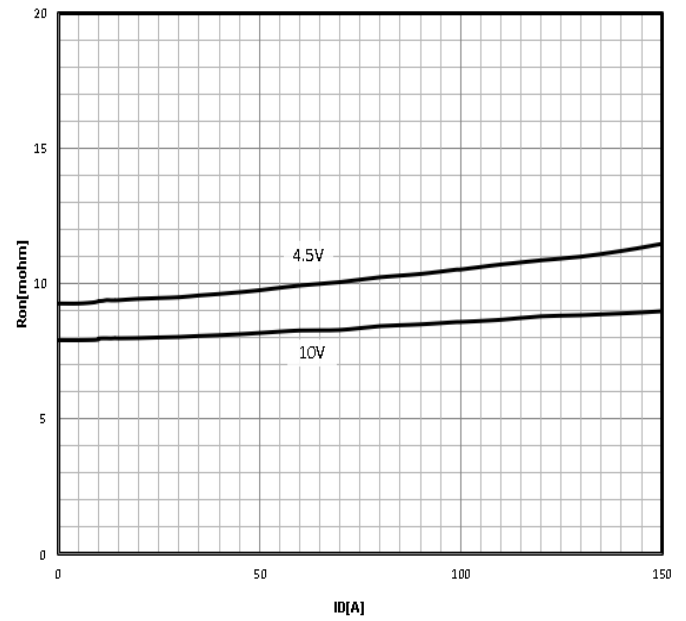
a2: VDD=50V, L=0.3mH, Rg=25Ω, Starting TJ=25 °C

Characteristics Curve:

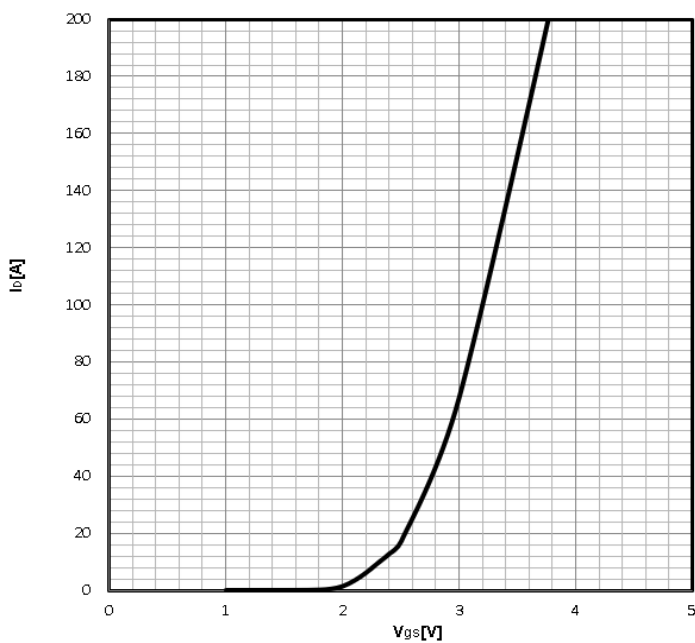
Typ. output characteristics
 $I_D = f(V_{DS})$



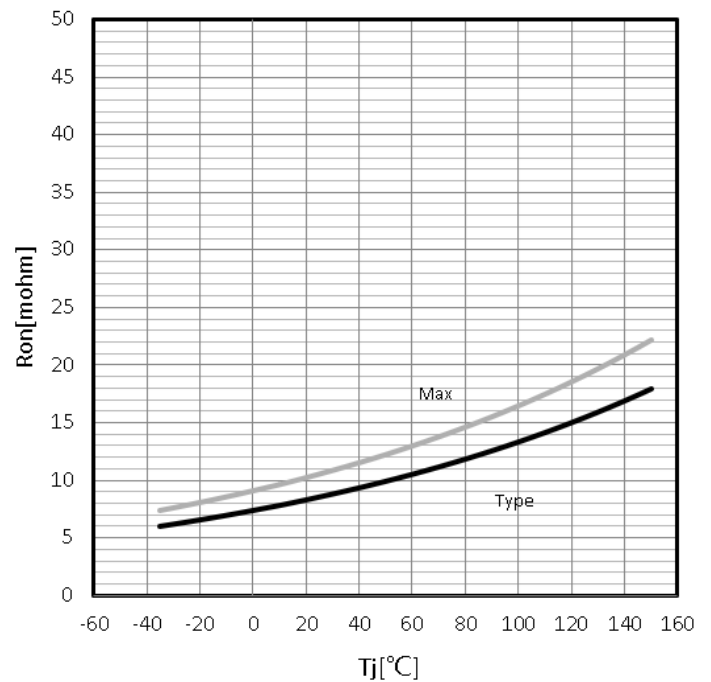
Typ. drain-source on resistance
 $R_{DS(on)} = f(I_D)$



Typ. transfer characteristics
 $I_D = f(V_{GS})$



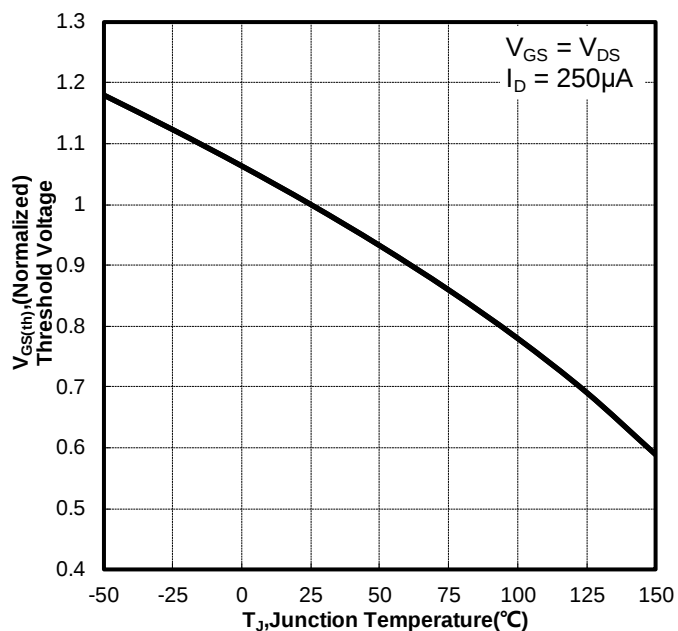
Drain-source on-state resistance
 $R_{DS(on)} = f(T_j); I_D = 20A; V_{GS} = 10V$



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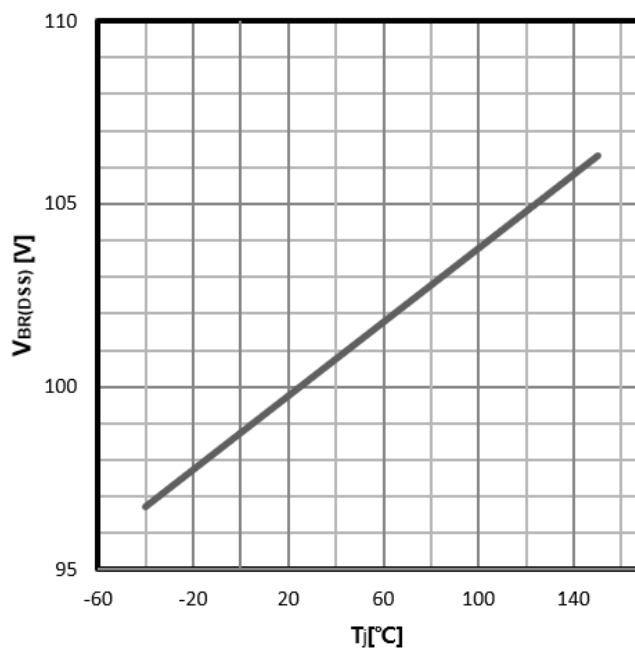
Gate Threshold Voltage

$$V_{TH}=f(T_j); I_D=250\mu A$$



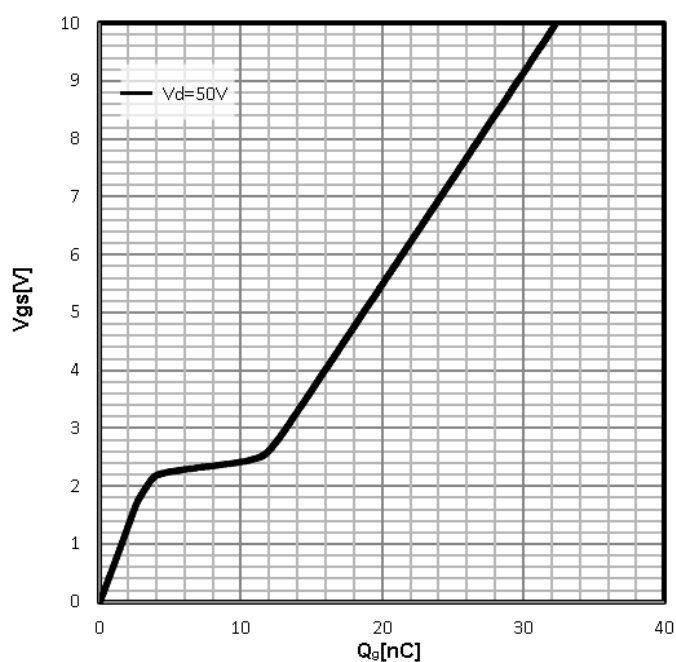
Drain-source breakdown voltage

$$V_{BR(DSS)}=f(T_j); I_D=250\mu A$$



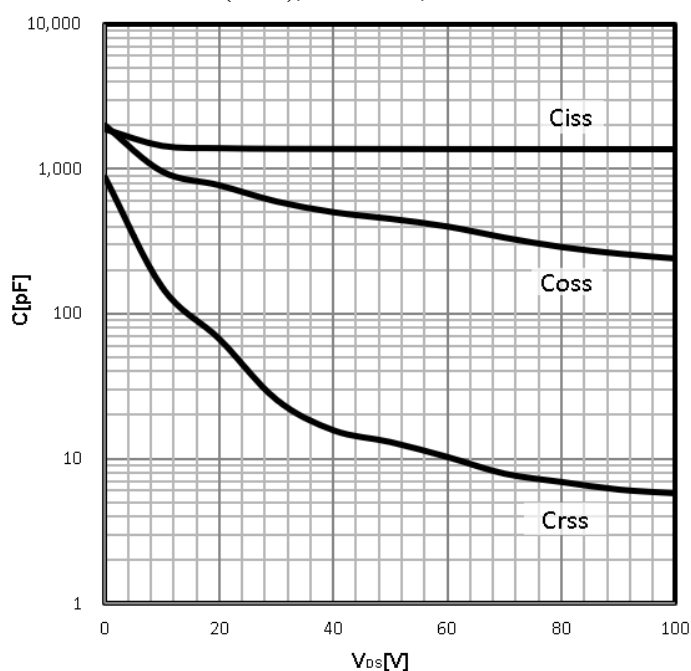
Typ. gate charge

$$V_{GS}=f(Q_g); I_D=10A$$



Typ. capacitances

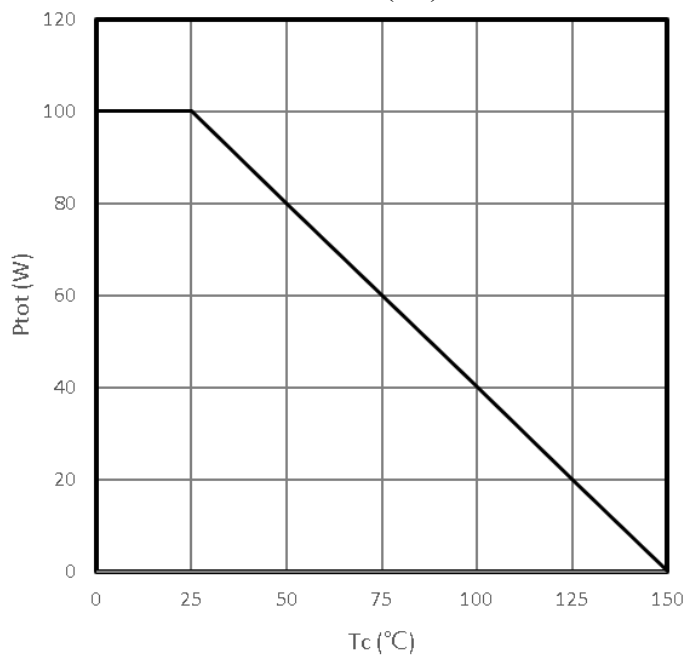
$$C=f(V_{DS}); V_{GS}=0V; f=1MHz$$





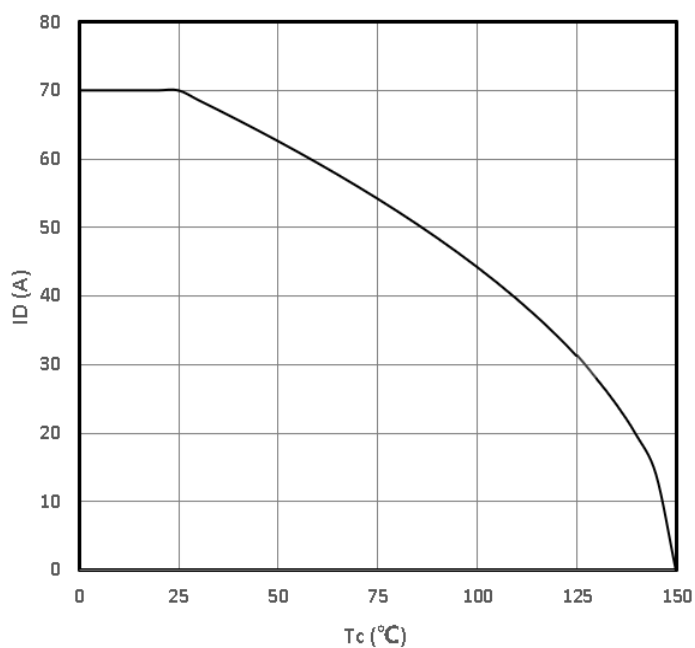
Power Dissipation

$$P_{tot}=f(T_C)$$



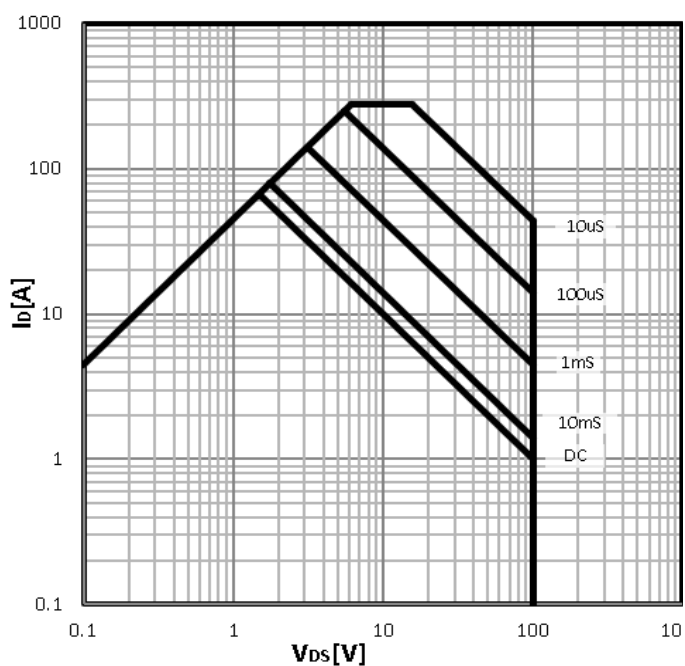
Maximum Drain Current

$$I_D=f(T_C)$$



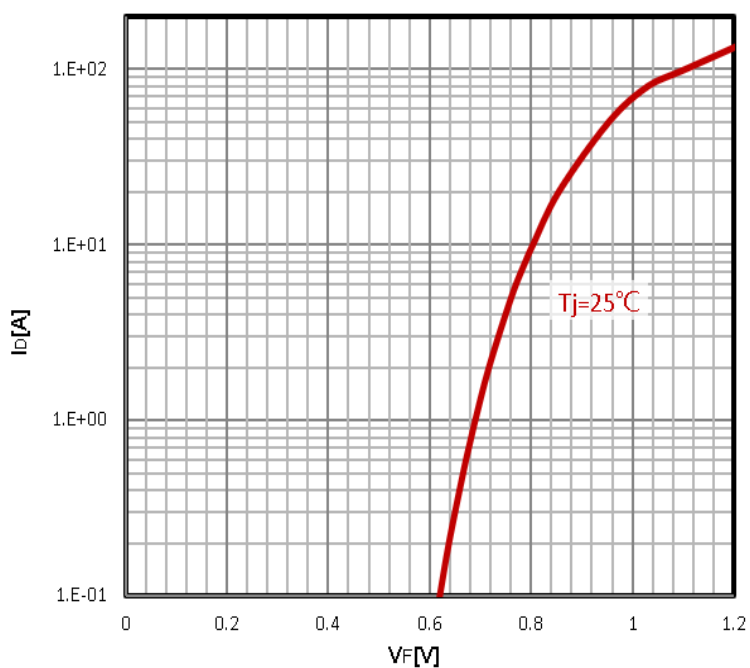
Safe operating area

$$I_D=f(V_{DS})$$



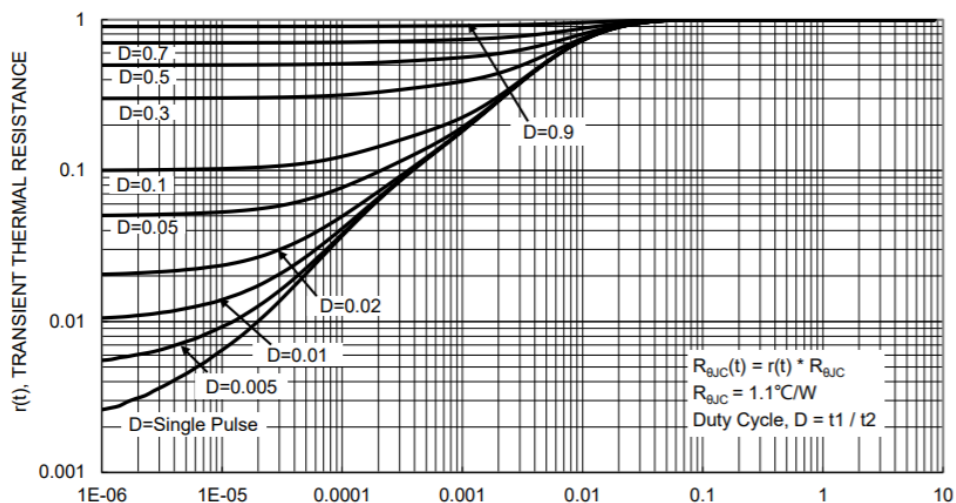
Body Diode Forward Voltage Variation

$$I_F=f(V_{GS})$$

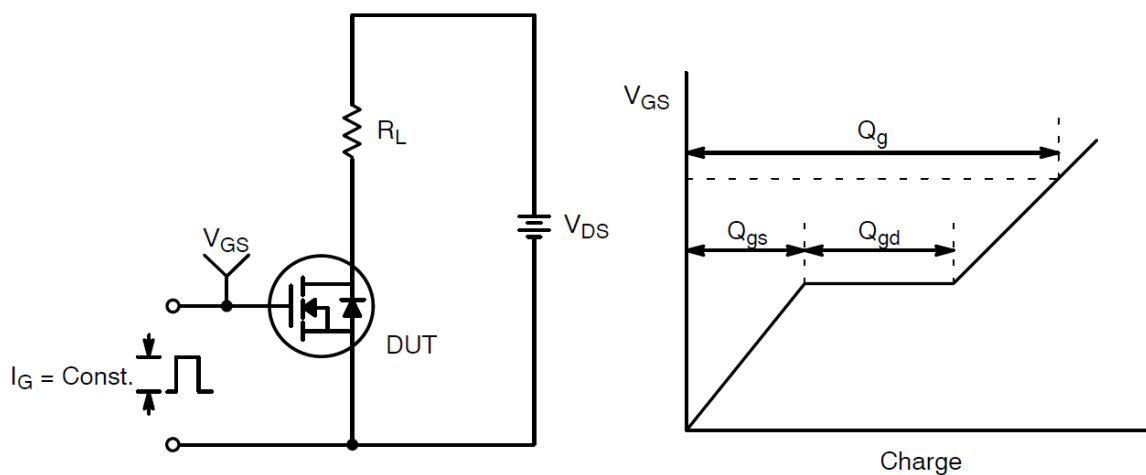


Max. transient thermal impedance

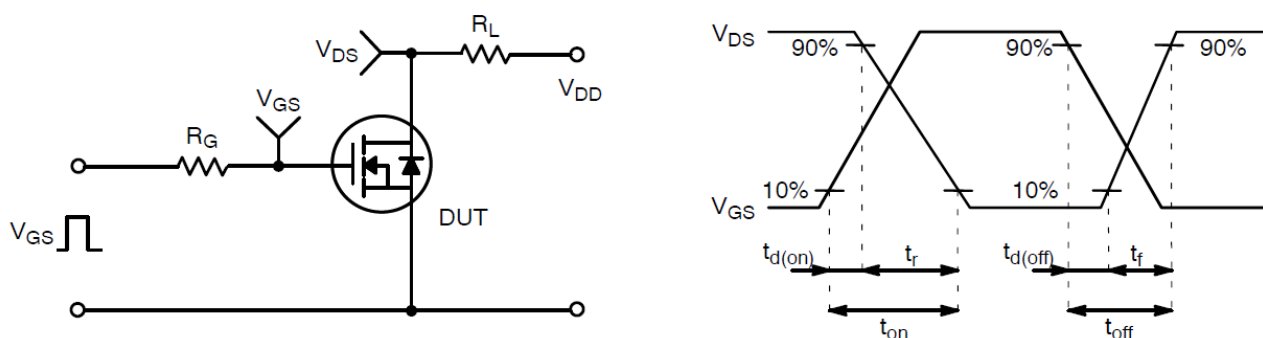
$$Z_{thJC} = f(t_p)$$



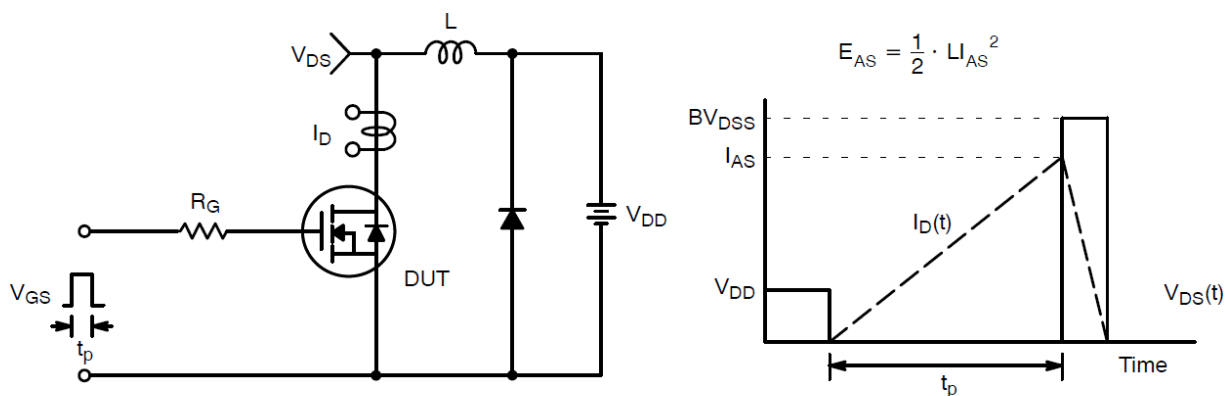
Test Circuit and Waveform:



Gate Charge Test Circuit & Waveform

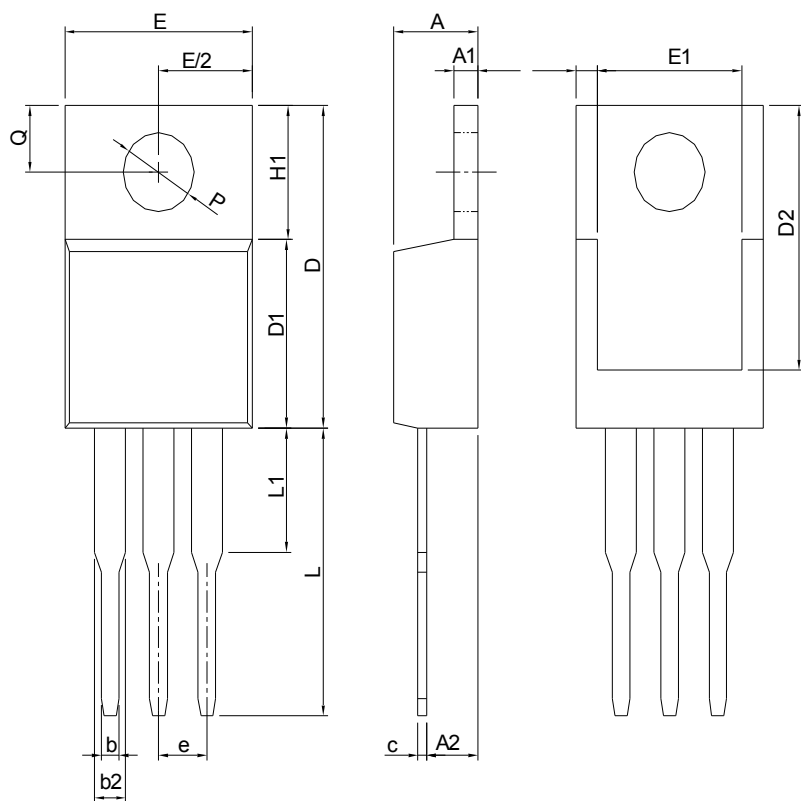


Resistive Switching Test Circuit & Waveforms



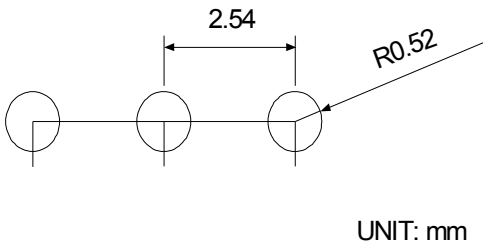
Unclamped Inductive Switching Test Circuit & Waveforms

Package Information:TO-220AB



SYMBOL	TO-220			
	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	3.56	4.83	0.140	0.190
A1	0.51	1.40	0.020	0.055
A2	2.03	2.92	0.080	0.115
b	0.38	1.02	0.015	0.040
b2	1.14	1.78	0.045	0.070
c	0.36	0.61	0.014	0.024
D	14.22	16.51	0.560	0.650
D1	8.38	9.02	0.330	0.355
D2	12.19	13.65	0.480	0.537
E	9.65	10.67	0.380	0.420
E1	6.86	8.89	0.270	0.350
e	2.54 BSC		0.100 BSC	
H1	5.84	6.86	0.230	0.270
L	12.70	14.73	0.500	0.580
L1	-	6.35	-	0.250
P	3.53	4.09	0.139	0.161
Q	2.54	3.43	0.100	0.135

RECOMMENDED LAND PATTERN



Note: Follow JEDEC TO-220 AB.